

Data sheet acquired from Harris Semiconductor

February 1998 - Revised May 2003

High-Speed CMOS Logic Octal-Bus Transceiver/Registers, Three-State

Features

- CD74HC652, CD74HCT652 Non-Inverting
- Independent Registers for A and B Buses
- · Three-State Outputs
- Drives 15 LSTTL Loads
- Typical Propagation Delay = 12ns at V_{CC} = 5V, C_L = 15pF
- Fanout (Over Temperature Range)
 - Standard Outputs................ 10 LSTTL Loads
 - Bus Driver Outputs 15 LSTTL Loads
- Wide Operating Temperature Range ... -55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- · Alternate Source is Philips
- HC Types
 - 2V to 6V Operation
 - High Noise Immunity: N_{IL} = 30%, N_{IH} = 30% of V_{CC} at V_{CC} = 5V
- HCT Types
 - 4.5V to 5.5V Operation
 - Direct LSTTL Input Logic Compatibility,
 V_{IL}= 0.8V (Max), V_{IH} = 2V (Min)
 - CMOS Input Compatibility, $I_I \leq 1 \mu \text{A}$ at $V_{\mbox{\scriptsize OL}}, \, V_{\mbox{\scriptsize OH}}$

CD74HC652 (PDIP) CD74HCT652

Pinout

(SOIC) **TOP VIEW** CAB 1 24 V_{CC} SAB 2 23 СВА 22 SBA OE_{AB} 3 21 OE_{BA} A0 4 A1 5 20 B0 19 B1 A2 6 A3 7 18 B2

A4 8

A5 9 A6 10

A7 11 GND 12 Description

The CD74HC652 and CD74HCT652 three-state, octal-bus transceiver/registers use silicon-gate CMOS technology to achieve operating speeds similar to LSTTL with the low power consumption of standard CMOS integrated circuits. The CD74HC652 and CD74HCT652 have non-inverting outputs. These devices consists of bus transceiver circuits, D-type flipflops, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. Output Enables OEAB and OEBA are provided to control the transceiver functions. SAB and SBA control pins are provided to select whether real-time or stored data is transferred. The circuitry used for select control will eliminate the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. A LOW input level selects real-time data, and a HIGH selects stored data. The following examples demonstrates the four fundamentals bus-management functions that can be performed with the octal-bus transceivers and registers.

Data on the A or B data bus, or both, can be stored in the internal D flip-flops by low-to-high transitions at the appropriate clock pins (CAB or CBA) regardless of the select of the control pins. When SAB and SBA are in the real-time transfer mode, it is also possible to store data without using the D-type flip-flops by simultaneously enabling $\mathsf{OE}_{\mathsf{AB}}$ and $\mathsf{OE}_{\mathsf{BA}}$. In this configuration, each output reinforces its input. Thus, when all other data sources to the two sets of bus lines are at high impedance, each set of bus lines will remain at its last state.

Ordering Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE
CD74HC652EN	-55 to 125	24 Ld PDIP
CD74HCT652M	-55 to 125	24 Ld SOIC
CD74HCT652M96	-55 to 125	24 Ld SOIC

NOTE: When ordering, use the entire part number. The suffix 96 denotes tape and reel.

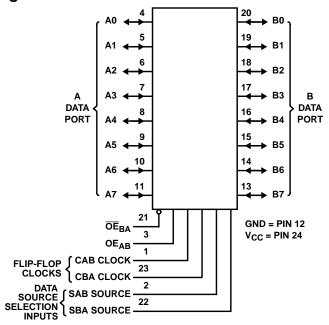
17 B3

16 B4

15 B5 14 B6

13 B7

Functional Diagram



FUNCTION TABLE

		INP	UTS			DAT	A I/O	OPERATION (OR FUNCTION	
OE _{AB}	OEBA	CAB	СВА	SAB	SBA	A0 THRU A7	B0 THRU B7	651	652	
L	Н	H or L	H or L	Х	Х	Input	Input	Isolation (Note 1)	Isolation (Note 1)	
L	Н	1	1	Х	Х			Store A and B Data	Store A and B Data	
Х	Н	1	H or L	Х	Х	Input	Unspecified (Note 2)	Store A, Hold B	Store A, Hold B	
Н	Н	1	1	X (Note 3)	Х	Input	Output	Store A in Both Registers	Store A in Both Registers	
L	Х	H or L	1	Х	Х	Unspecified (Note 2)	Input	Hold A, Store B	Hold A, Store B	
L	L	1	1	Х	X (Note 3)	Output	Input	Store B in Both Registers	Store B in Both Registers	
L	L	Х	Х	Х	L	Output	Input	Real-Time B Data to A Bus	Real-Time B Data to A Bus	
L	L	Х	H or L	Х	Н			Stored B Data to A Bus	Stored B Data to A Bus	
Н	Н	Х	Х	L	Х	Input	Output	Real-Time A Data to B Bus	Real-Time A Data to B Bus	
Н	Н	H or L	Х	Н	Х			Stored A Data to B Bus	Stored A Data to B Bus	
Н	L	H or L	H or L	Н	Н	Output	Output	Stored A Data to B Bus and	Stored A Data to B Bus	
								Stored B Data to A Bus	Stored B Data to A Bus	

NOTES:

- 1. To prevent excess currents in the High-Z (isolation) modes, all I/O terminals should be terminated with $10k\Omega$ to $1M\Omega$ resistors.
- 2. The data output functions may be enabled or disabled by various signals at the OE_{AB} or $\overline{\text{OE}}_{\text{BA}}$ inputs. Data input functions are always enabled; i.e., data at the bus pins will be stored on every low-to-high transition on the clock inputs.
- Select Control = L: Clocks can occur simultaneously.
 Select Control = H: Clocks must be staggered in order to load both registers.

Absolute Maximum Ratings DC Supply Voltage, V_{CC} (Voltages Referenced to Ground) -0.5V to 7V DC Input Diode Current, I_{IK} DC Drain Current, IO For $-0.5V < V_O < V_{CC} + 0.5V$±35mA DC Output Diode Current, IOK For $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$±20mA DC Output Source or Sink Current per Output Pin, IO For $V_O > -0.5V$ or $V_O < V_{CC} + 0.5V$±25mA **Operating Conditions** Supply Voltage Range, V_{CC} HC Types2V to 6V

 2V
 1000ns (Max)

 4.5V
 500ns (Max)

 6V
 400ns (Max)

Thermal Information

Thermal Resistance (Typical)	θ_{JA} (°C/W)
EN (PDIP) Package (Note 4)	67
M (SOIC) Package (Note 5)	46
Maximum Junction Temperature (Hermetic Package or I	Die) 175 ⁰ C
Maximum Junction Temperature (Plastic Package)	150 ^o C
Maximum Storage Temperature Range	65°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300°C
(SOIC - Lead Tips Only)	

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTES

Input Rise and Fall Time

- 4. The package thermal impedance is calculated in accordance with JESD 51-3.
- 5. The package thermal impedance is calculated in accordance with JESD 51-7.

DC Electrical Specifications

	• • • • • • • • • • • • • • • • • • •		ST ITIONS		25°C			-40°C T	O 85°C	-55°C TO 125°C		
PARAMETER	SYMBOL	V _I (V)	V _{IS} (V)	V _{CC} (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
HC TYPES												
High Level Input	V _{IH}	-	-	2	1.5	-	-	1.5	-	1.5	-	V
Voltage				4.5	3.15	-	-	3.15	-	3.15	-	٧
				6	4.2	-	-	4.2	-	4.2	-	٧
Low Level Input		-	-	2	-	-	0.3	-	0.3	-	0.3	٧
Voltage				4.5	-	-	0.9	-	0.9	-	0.9	٧
				6	-	-	1.2	-	1.2	-	1.2	٧
High Level Output Voltage CMOS Loads	V _{OH}	V _{IH} or	-0.02	2	1.9	-	-	1.9	-	1.9	-	٧
		V _{IL}	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	٧
			-0.02	6	5.9	-	-	5.9	-	5.9	-	٧
High Level Output	1		-	-	-	-	-	-	-	-	-	٧
Voltage TTL Loads			-6	4.5	3.98	-	-	3.84	-	3.7	-	٧
			-7.8	6	5.48	-	-	5.34	-	5.2	-	٧
Low Level Output	V _{OL}	V _{IH} or	0.02	2	-	-	0.1	-	0.1	-	0.1	٧
Voltage CMOS Loads		V_{IL}	0.02	4.5	-	-	0.1	-	0.1	-	0.1	٧
			0.02	6	-	-	0.1	-	0.1	-	0.1	٧
Low Level Output	1		-	-	-	-	-	-	-	-	-	٧
Voltage TTL Loads			6	4.5	-	-	0.26	-	0.33	-	0.4	٧
			7.8	6	-	-	0.26	-	0.33	-	0.4	V

DC Electrical Specifications (Continued)

		TEST CONDITIONS				25°C		-40°C T	O 85°C	-55°C T	O 125°C		
PARAMETER	SYMBOL	V _I (V)	V _{IS} (V)	V _{CC} (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS	
Input Leakage Current	lı	V _{CC} or GND	-	6	-	-	±0.1	-	±1	-	±1	μА	
Quiescent Device Current	Icc	V _{CC} or GND	0	6	-	-	8	-	80	-	160	μА	
Three- State Leakage Current	V _{IL} or V _{IH}	V _O = V _{CC} or GND	-	6	-	-	±0.5	-	±5.0	-	±10	μА	
HCT TYPES											•		
High Level Input Voltage	V _{IH}	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V	
Low Level Input Voltage	V _{IL}	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V	
High Level Output Voltage CMOS Loads	V _{OH}	V _{IH} or V _{IL}	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V	
High Level Output Voltage TTL Loads			-6	4.5	3.98	-	-	3.84	-	3.7	-	V	
Low Level Output Voltage CMOS Loads	V _{OL}	V _{IH} or V _{IL}	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V	
Low Level Output Voltage TTL Loads			6	4.5	-	-	0.26	-	0.33	-	0.4	V	
Input Leakage Current	II	V _{CC} and GND	0	5.5	-		±0.1	-	±1	-	±1	μА	
Quiescent Device Current	Icc	V _{CC} or GND	0	5.5	-	-	8	-	80	-	160	μА	
Three- State Leakage Current	V _{IL} or V _{IH}	V _O = V _{CC} or GND	-	5.5	-	-	±0.5	-	±5.0	-	±10	μА	
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI _{CC} (Note 6)	V _{CC} -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	μА	

NOTE:

6. For dual-supply systems theoretical worst case ($V_I = 2.4V$, $V_{CC} = 5.5V$) specification is 1.8mA.

HCT Input Loading Table

INPUT	UNIT LOADS						
OE BA	1.3						
OE _{AB}	0.75						
Clock A to B, B to A	0.6						
Select A, Select B	0.45						
Inputs A ₀ -A ₇ , B ₀ -B ₇	0.3						

NOTE: Unit Load is ΔI_{CC} limit specified in DC Electrical Specifications table, e.g., $360\mu A$ max at $25^{\circ}C$.

Prerequisite for Switching Specifications

				25°C		-40	°C TO 8	5°C	-55°C TO 125°C			
PARAMETER	SYMBOL	V _{CC} (V)	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
HC TYPES	•			•				-				
Maximum Clock	f _{MAX}	2	6	-	-	5	-	-	4	-	-	MHz
Frequency		4.5	30	-	-	25	-	-	20	-	-	MHz
		6	35	-	-	29	-	-	23	-	-	MHz
Setup Time	tsu	2	60	-	-	75	-	-	90	-	-	ns
Data to Clock		4.5	12	-	-	15	-	-	18	-	-	ns
		6	10	-	-	13	-	-	15	-	-	ns
Hold Time Data to Clock	t _H	2	35	-	-	45	-	-	55	-	-	ns
		4.5	7	-	-	9	-	-	11	-	-	ns
		6	6	-	-	8	-	-	9	-	-	ns
Clock Pulse Width	t _W	2	80	-	-	100	-	-	120	-	-	ns
		4.5	16	-	-	20	-	-	24	-	-	ns
		6	14	-	-	17	-	-	20	-	-	ns
HCT TYPES												
Maximum Clock Frequency	f _{MAX}	4.5	25	-	-	20	-	-	17	-	-	MHz
Setup Time Data to Clock	t _{SU}	4.5	12	-	-	15	-	-	18	-	-	ns
Hold Time Data to Clock	t _H	4.5	5	-	-	5	-	-	5	-	-	ns
Clock Pulse Width	t _W	4.5	25	-	-	31	-	-	38	-	-	ns

Switching Specifications Input $t_{\text{r}}, \, t_{\text{f}} = 6 \text{ns}$

		TEST	v _{cc}		25°C			-40°C TO 85°C		-55°C TO 125°C	
PARAMETER	SYMBOL	CONDITIONS	(V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
HC TYPES							-	-	-		
Propagation Delay, Store A Data to B Bus Store B Data to A Bus	t _{PLH} , t _{PHL}	C _L = 50pF	2	-	-	220	-	275	-	300	ns
			4.5	-	-	44	-	55	-	66	ns
			6	-	-	37	-	47	-	5.6	ns
		C _L = 15pF	5	-	18	-	-	-	-	-	ns
Propagation Delay,	t _{PLH} , t _{PHL}	C _L = 50pF	2	-	-	135	-	170	-	205	ns
A Data to B Bus B Data to A Bus			4.5	-	-	27	-	34	-	41	ns
			6	-	-	23	-	29	-	35	ns
		C _L = 15pF	5	-	12	-	-	-	-	-	ns
Propagation Delay,	t _{PLH} , t _{PHL}	C _L = 50pF	2	-	-	170	-	215	-	255	ns
Select to Data			4.5	-	-	34	-	43	-	51	ns
			6	-	-	29	-	37	-	43	ns
		C _L = 15pF	5	-	14	-	-	-	-	-	ns

Switching Specifications Input $t_{\text{r}},\,t_{\text{f}}$ = 6ns (Continued)

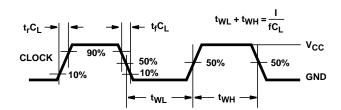
		TEST	v _{cc}		25 ⁰ C		-40°C 1	O 85°C	-55°C T		
PARAMETER	SYMBOL	CONDITIONS	(8)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
Three-State Disabling Time Bus	t _{PLZ} , t _{PHZ}	C _L = 50pF	2	-	-	175	-	220	-	265	ns
to Output or Register to Output			4.5	-	-	35	-	44	-	53	ns
			6	-	-	30	-	37	-	45	ns
		C _L = 15pF	5	-	14	-	-	-	-	-	ns
Three-State Enabling Time Bus	t _{PZL} , t _{PZH}	C _L = 50pF	2	-	-	175	-	220	-	265	ns
to Output or Register to Output			4.5	-	-	35	-	44	-	53	ns
			6	-	-	30	-	37	-	45	ns
		C _L = 15pF	5	-	14	-	-	-	-	-	ns
Output Transition Time	t _{TLH} , t _{THL}	$C_L = 50pF$	2	-	-	60	-	75	-	90	ns
			4.5	-	-	12	-	15	-	18	ns
			6	-	-	10	-	13	-	15	ns
Three-State Output Capacitance	CO	-	ı	-	-	20	1	20	-	20	pF
Input Capacitance	Cl	-	i	-	-	10	ı	10	-	10	pF
Maximum Frequency	f _{MAX}	C _L = 15pF	5	-	60	-	-	-	-	-	MHz
Power Dissipation Capacitance (Notes 7, 8)	C _{PD}	-	5	-	52	-	-	-	-	-	pF
HCT TYPES											
Propagation Delay,	t _{PLH} , t _{PHL}	C _L = 50pF	4.5	-	-	44	-	55	-	66	ns
Store A Data to B Bus Store B Data to A Bus		C _L = 15pF	5	-	18	-	-	-	-	-	ns
Propagation Delay,	t _{PLH} , t _{PHL}	C _L = 50pF	4.5	-	-	37	-	46	-	56	ns
A Data to B Bus B Data to A Bus		C _L = 15pF	5	-	15	-	-	-	-	-	ns
Propagation Delay,	t _{PLH} , t _{PHL}	C _L = 50pF	4.5	-	-	46	-	58	-	69	ns
Select to Data		C _L = 15pF	5	-	19	-	-	-	-	-	ns
Three-State Disabling Time Bus	t _{PLZ} , t _{PHZ}	C _L = 50pF	4.5	-	-	35	-	44	-	53	ns
to Output or Register to Output		C _L = 15pF	5	-	14	-	-	-	-	-	ns
Three-State Enabling Time Bus	t _{PZL} , t _{PZH}	C _L = 50pF	4.5	-	-	45	-	56	-	68	ns
to Output or Register to Output		C _L = 15pF	5	-	19	-	-	-	-	-	ns
Output Transition Time	t _{TLH} , t _{THL}	C _L = 50pF	4.5	-	-	12	-	15	-	18	ns
Three-State Output Capacitance	CO	-	=	-	-	20	-	20	-	20	pF
Input Capacitance	Cl	-	-	-	-	10	-	10	-	10	pF
Maximum Frequency	f _{MAX}	C _L = 15pF	5	-	45	-	-	-	-	-	MHz
Power Dissipation Capacitance (Notes 7, 8)	C _{PD}	-	5	-	52	-	-	-	-	-	pF

NOTES:

^{7.} $C_{\mbox{\scriptsize PD}}$ is used to determine the dynamic power consumption, per package.

^{8.} $P_D = V_{CC}^2 C_{PD} f_i + \sum V_{CC}^2 C_L f_o$ where f_i = input frequency, f_o = output frequency, C_L = output load capacitance, C_S = switch capacitance, V_{CC} = supply voltage.

Test Circuits and Waveforms



NOTE: Outputs should be switching from 10% V $_{CC}$ to 90% V $_{CC}$ in accordance with device truth table. For f $_{MAX}$, input duty cycle = 50%.

FIGURE 2. HC CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH

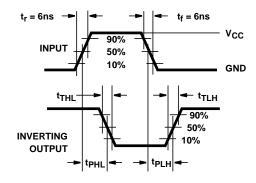
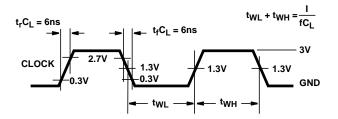


FIGURE 4. HC TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC



NOTE: Outputs should be switching from 10% V $_{CC}$ to 90% V $_{CC}$ in accordance with device truth table. For f $_{MAX}$, input duty cycle = 50%.

FIGURE 3. HCT CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH

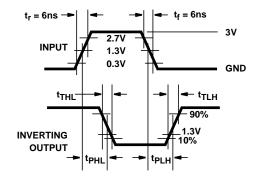
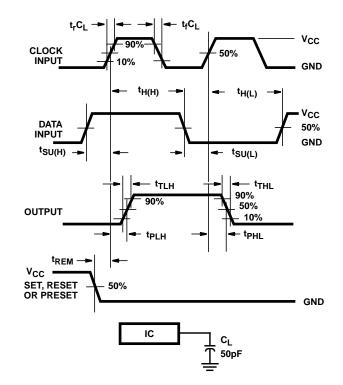


FIGURE 5. HCT TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

CLOCK

Test Circuits and Waveforms (Continued)

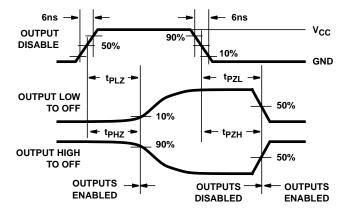


INPUT GND t_{H(L)} t_{H(H)} **3V** DATA 1.3V **INPUT** GND tSU(L) tSU(H) t_{TLH} - t_{THL} 90% 90% .3V 10% OUTPUT t_{PHL} ^tREM **3V** SET, RESET **OR PRESET** GND IC $\textbf{C}_{\textbf{L}}$ 50pF

3V

FIGURE 6. HC SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS

FIGURE 7. HCT SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS



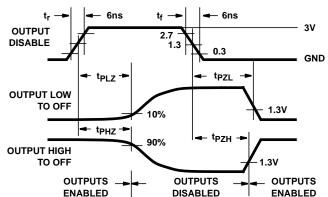
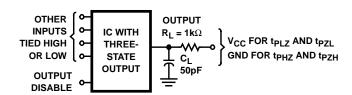


FIGURE 8. HC THREE-STATE PROPAGATION DELAY WAVEFORM

FIGURE 9. HCT THREE-STATE PROPAGATION DELAY WAVEFORM



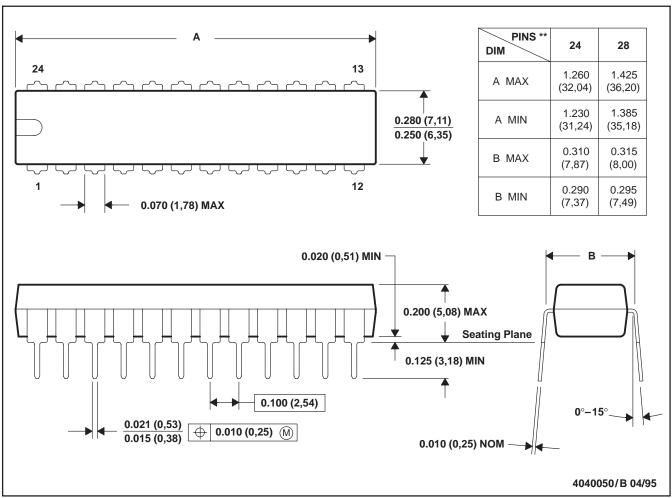
NOTE: Open drain waveforms t_{PLZ} and t_{PZL} are the same as those for three-state shown on the left. The test circuit is Output $R_L = 1k\Omega$ to V_{CC} , $C_L = 50pF$.

FIGURE 10. HC AND HCT THREE-STATE PROPAGATION DELAY TEST CIRCUIT

NT (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

24 PINS SHOWN

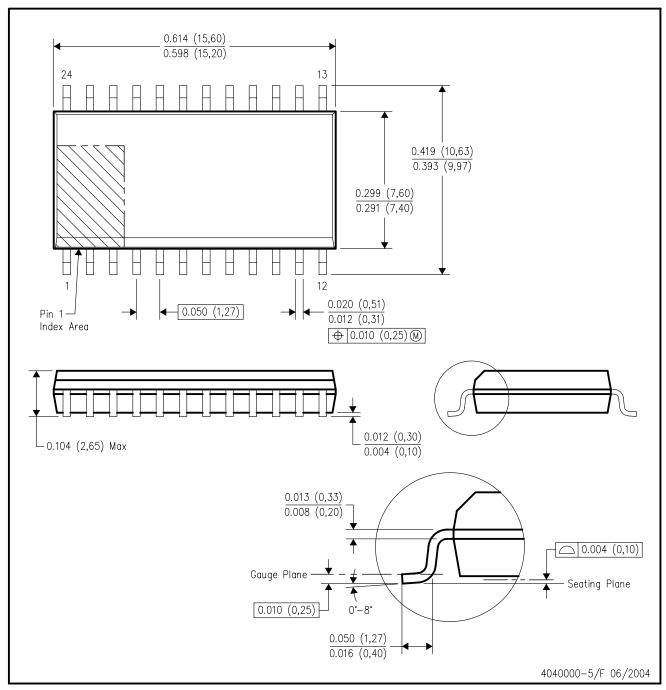


NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

DW (R-PDSO-G24)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.



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